

**Search Notes**

Application/Control No.

10/511,678

Examiner

Son T. Nguyen

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

3643

**SEARCHED**

Class	Subclass	Date	Examiner
119	253-256	3/30/2007	STN
428	15-17 457		
	458		
446	153 156		
	158 159		
427	304		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search, see printouts	3/30/2007	STN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner